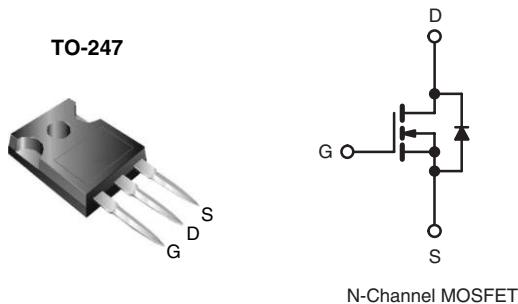


Power MOSFET

PRODUCT SUMMARY	
V _{DS} (V)	600
R _{DS(on)} (Ω)	V _{GS} = 10 V 0.60
Q _g (Max.) (nC)	84
Q _{gs} (nC)	18
Q _{gd} (nC)	36
Configuration	Single



FEATURES

- Ultra Low Gate Charge
- Reduced Gate Drive Requirement
- Enhanced 30 V V_{GS} Rating
- Reduced C_{iss}, C_{oss}, C_{rss}
- Isolated Central Mounting Hole
- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Lead (Pb)-free Available



RoHS*
COMPLIANT

DESCRIPTION

This new series of low charge Power MOSFETs achieve significantly lower gate charge over conventional MOSFETs. Utilizing advanced Power MOSFET technology the device improvements allow for reduced gate drive requirements, faster switching speeds and increased total system savings. These device improvements combined with the proven ruggedness and reliability of Power MOSFETs offer the designer a new standard in power transistors for switching applications.

The TO-247 package is preferred for commercial-industrial applications where higher power levels preclude the use of TO-220 devices. The TO-247 is similar but superior to the earlier TO-218 package because its isolated mounting hole.

ORDERING INFORMATION

Package	TO-247
Lead (Pb)-free	IRFPC50LCPbF SiHFPC50LC-E3
SnPb	IRFPC50LC SiHFPC50LC

ABSOLUTE MAXIMUM RATINGS T_C = 25 °C, unless otherwise noted

PARAMETER	SYMBOL	LIMIT	UNIT
Drain-Source Voltage	V _{DS}	600	V
Gate-Source Voltage	V _{GS}	± 30	
Continuous Drain Current	V _{GS} at 10 V	T _C = 25 °C	A
		T _C = 100 °C	
Pulsed Drain Current ^a	I _{DM}	44	
Linear Derating Factor		1.5	W/°C
Single Pulse Avalanche Energy ^b	E _{AS}	920	mJ
Repetitive Avalanche Current ^c	I _{AR}	11	A
Repetitive Avalanche Energy ^a	E _{AR}	19	mJ
Maximum Power Dissipation	P _D	190	W
Peak Diode Recovery dV/dt ^c	dV/dt	3.0	V/ns
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to + 150	°C
Soldering Recommendations (Peak Temperature)	for 10 s	300 ^d	
Mounting Torque	6-32 or M3 screw	10	lbf · in
		1.1	N · m

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. V_{DD} = 25 V, starting T_J = 25 °C, L = 13 mH, R_G = 25 Ω, I_{AS} = 11 A (see fig. 12).

c. I_{SD} ≤ 11 A, dI/dt ≤ 100 A/μs, V_{DD} ≤ V_{DS}, T_J ≤ 150 °C.

d. 1.6 mm from case.

* Pb containing terminations are not RoHS compliant, exemptions may apply

IRFPC50LC, SiHFPC50LC

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Thermal Resistance Ratings

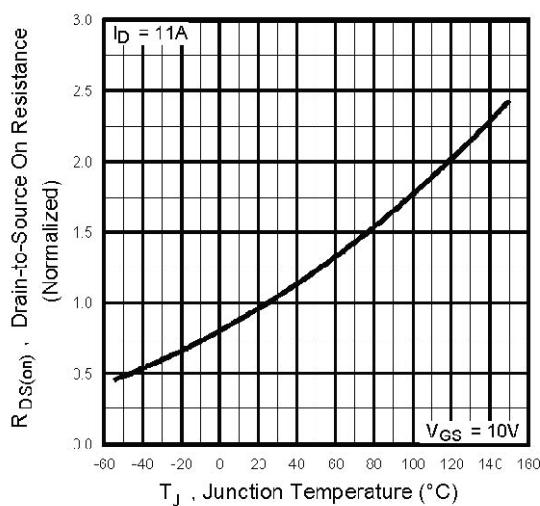
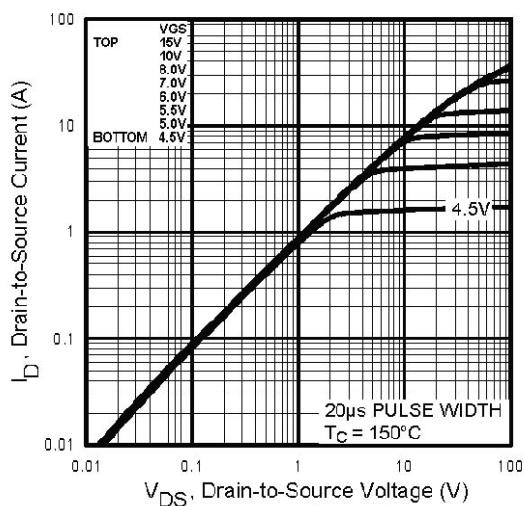
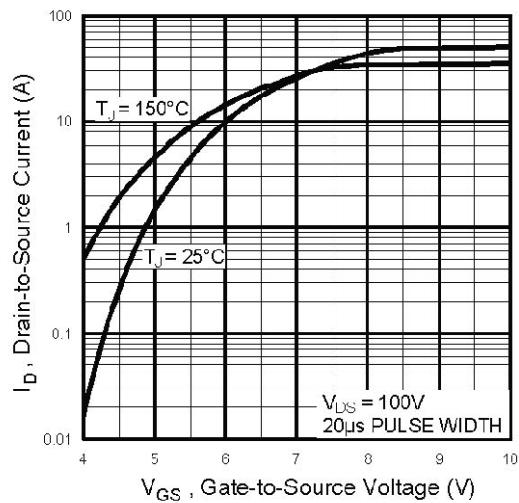
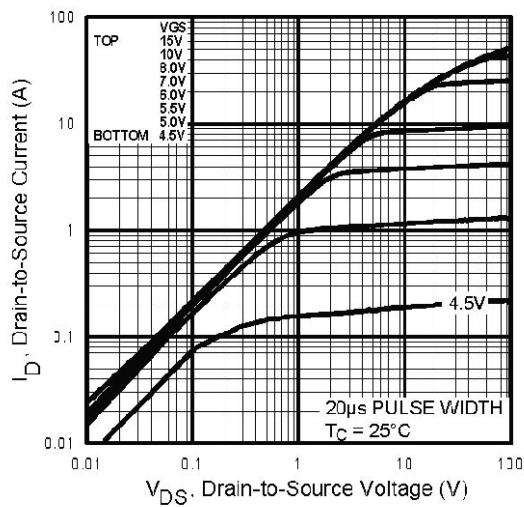
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R_{thJA}	-	40	°C/W
Case-to-Sink, Flat, Greased Surface	R_{thCS}	0.24	-	
Maximum Junction-to-Case (Drain)	R_{thJC}	-	0.65	

Specifications $T_J = 25^\circ\text{C}$, unless otherwise noted

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT	
Static								
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}$	$I_D = 250 \mu\text{A}$	600	-	-	V	
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to 25°C , $I_D = 1 \text{ mA}$		-	0.59	-	$^\circ\text{C}/\text{C}$	
Gate-Source Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}$, $I_D = 250 \mu\text{A}$		2.0	-	4.0	V	
Gate-Source Leakage	I_{GSS}	$V_{GS} = \pm 20 \text{ V}$		-	-	± 100	nA	
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 600 \text{ V}$, $V_{GS} = 0 \text{ V}$		-	-	25	μA	
		$V_{DS} = 480 \text{ V}$, $V_{GS} = 0 \text{ V}$, $T_J = 125^\circ\text{C}$		-	-	250		
Drain-Source On-State Resistance	$R_{DS(\text{on})}$	$V_{GS} = 10 \text{ V}$	$I_D = 6.6 \text{ A}^b$	-	-	0.60	Ω	
Forward Transconductance	g_{fs}	$V_{DS} = 100 \text{ V}$, $I_D = 6.6 \text{ A}^b$		7.0	-	-	S	
Dynamic								
Input Capacitance	C_{iss}	$V_{GS} = 0 \text{ V}$, $V_{DS} = 25 \text{ V}$, $f = 1.0 \text{ MHz}$, see fig. 5		-	2300	-	pF	
Output Capacitance	C_{oss}			-	270	-		
Reverse Transfer Capacitance	C_{rss}			-	28	-		
Total Gate Charge	Q_g	$V_{GS} = 10 \text{ V}$	$I_D = 11 \text{ A}$, $V_{DS} = 360 \text{ V}$, see fig. 6 and 13 ^b	-	-	84	nC	
Gate-Source Charge	Q_{gs}			-	-	18		
Gate-Drain Charge	Q_{gd}			-	-	36		
Turn-On Delay Time	$t_{d(\text{on})}$	$V_{DD} = 300 \text{ V}$, $I_D = 11 \text{ A}$, $R_G = 6.2 \Omega$, $R_D = 30 \Omega$, see fig. 10 ^b		-	17	-	ns	
Rise Time	t_r			-	32	-		
Turn-Off Delay Time	$t_{d(\text{off})}$			-	41	-		
Fall Time	t_f			-	26	-		
Internal Drain Inductance	L_D	Between lead, 6 mm (0.25") from package and center of die contact		-	5.0	-	nH	
Internal Source Inductance	L_S			-	13	-		
Drain-Source Body Diode Characteristics								
Continuous Source-Drain Diode Current	I_S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	11	A	
Pulsed Diode Forward Current ^a	I_{SM}			-	-	44		
Body Diode Voltage	V_{SD}	$T_J = 25^\circ\text{C}$, $I_S = 11 \text{ A}$, $V_{GS} = 0 \text{ V}^b$		-	-	1.4	V	
Body Diode Reverse Recovery Time	t_{rr}	$T_J = 25^\circ\text{C}$, $I_F = 11 \text{ A}$, $dI/dt = 100 \text{ A}/\mu\text{s}^b$		-	590	890	ns	
Body Diode Reverse Recovery Charge	Q_{rr}			-	4.5	6.8	μC	
Forward Turn-On Time	t_{on}	Intrinsic turn-on time is negligible (turn-on is dominated by L_S and L_D)						

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width $\leq 300 \mu\text{s}$; duty cycle $\leq 2\%$.

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted


IRFPC50LC, SiHFPC50LC

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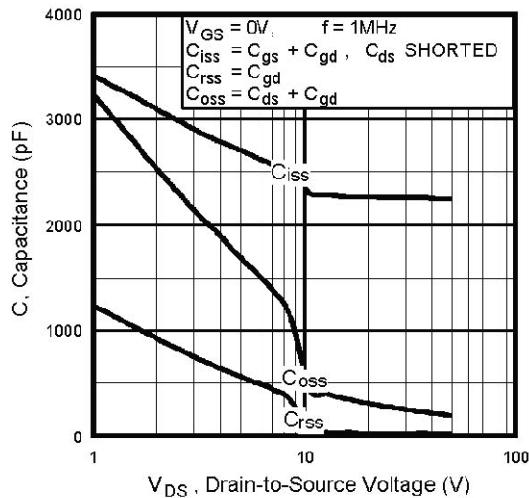


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

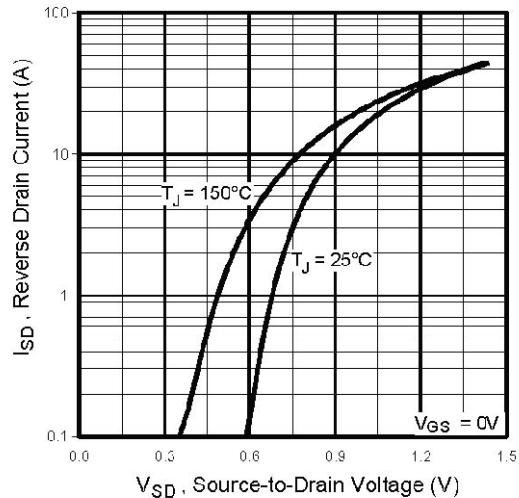


Fig. 7 - Typical Source-Drain Diode Forward Voltage

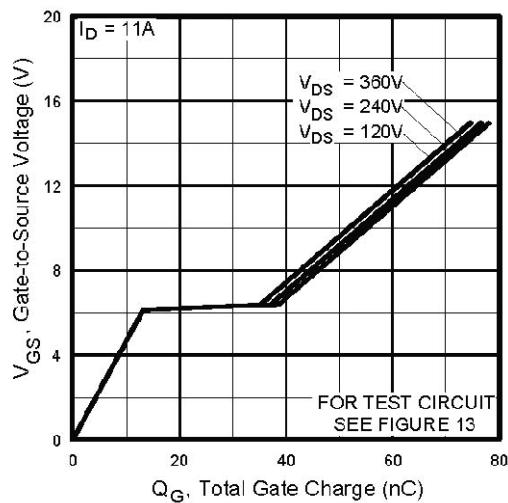


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

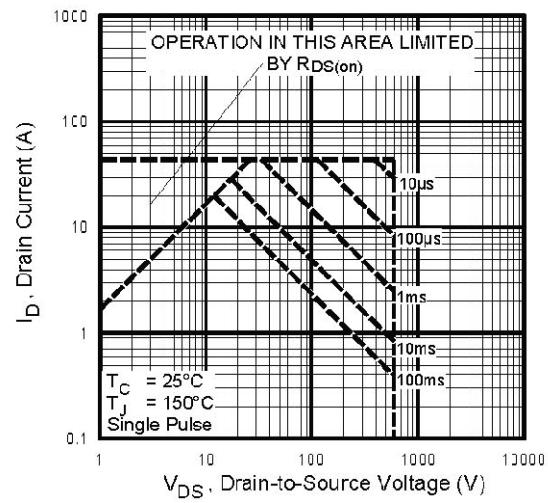
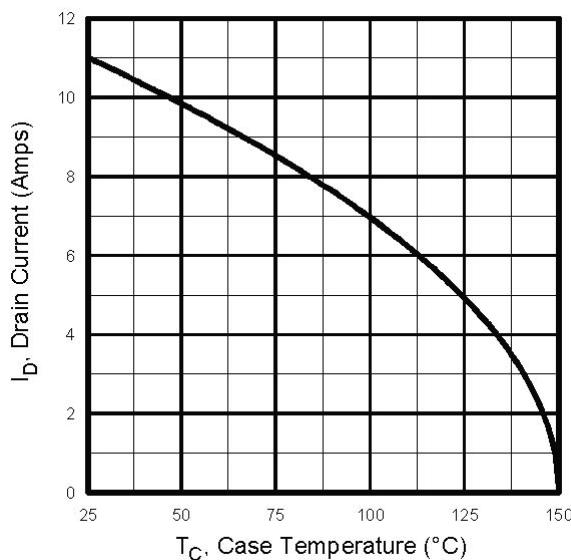
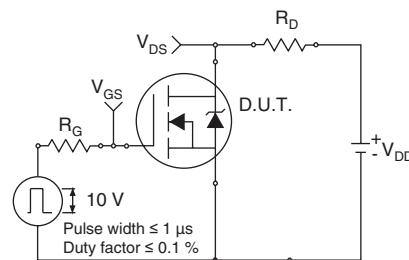
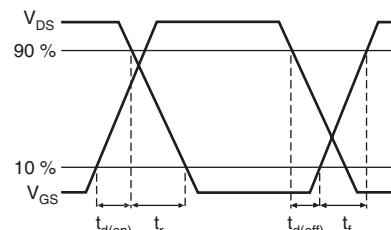
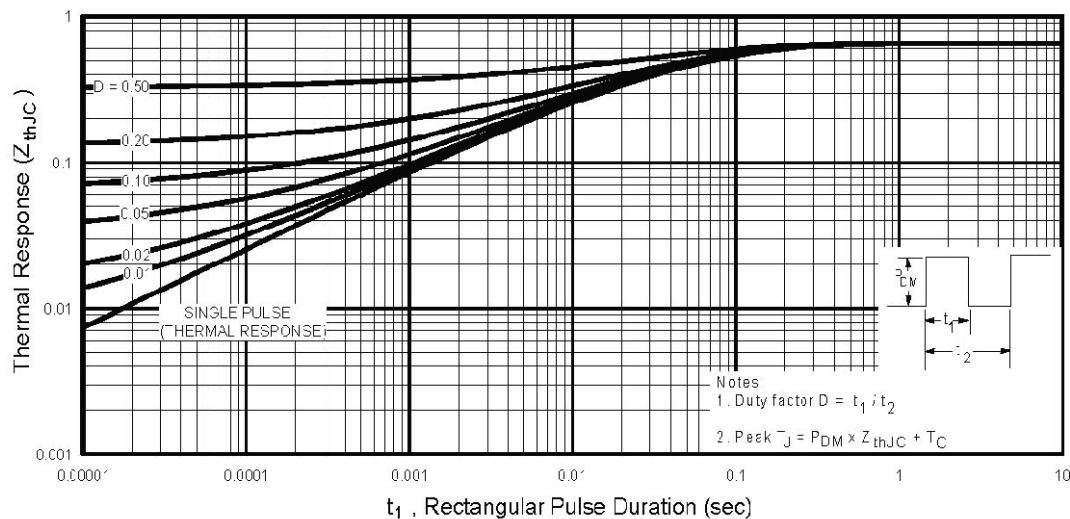
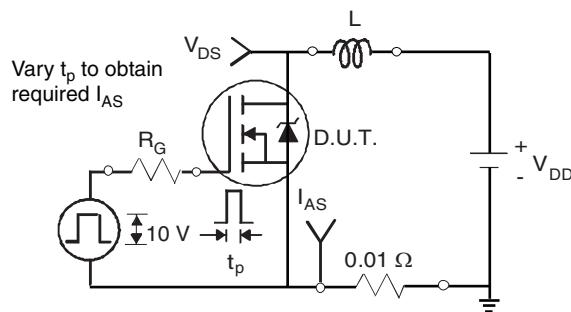
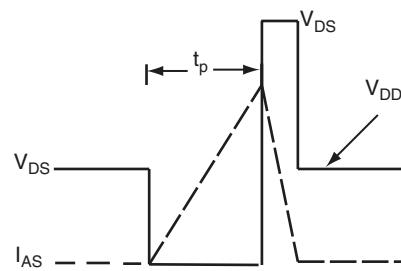


Fig. 8 - Maximum Safe Operating Area


Fig. 9 - Maximum Drain Current vs. Case Temperature

Fig. 10a - Switching Time Test Circuit

Fig. 10b - Switching Time Waveforms

Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

Fig. 12a - Unclamped Inductive Test Circuit

Fig. 12b - Unclamped Inductive Waveforms

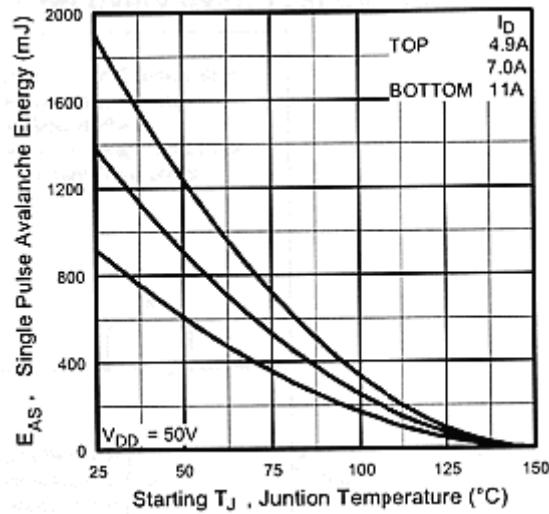


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

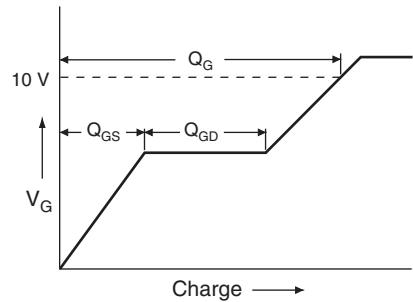


Fig. 13a - Basic Gate Charge Waveform

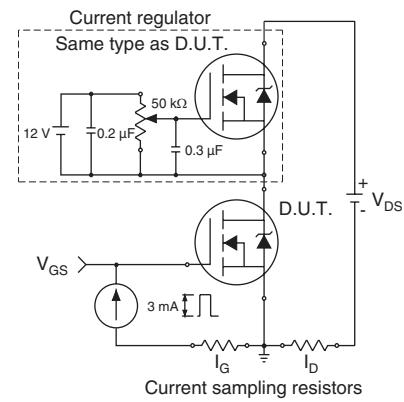
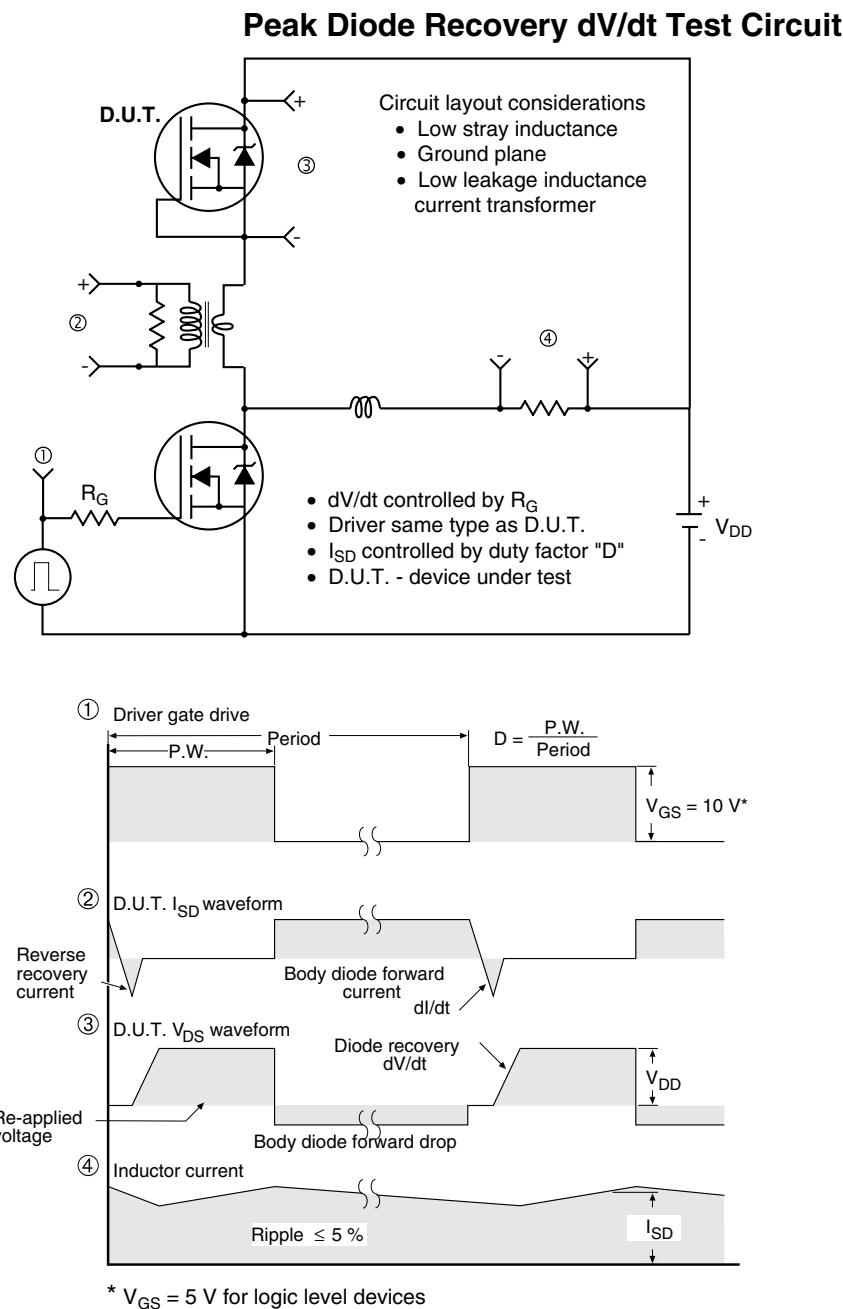


Fig. 13b - Gate Charge Test Circuit


Fig. 14 - For N-Channel

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